

# High Resolution X-ray Diffractometer



## *High Resolution X-ray Diffractometer at Center for Nanoscience & Nanotechnology*

X-Ray Diffractometer is the most important tool for performing diffraction analysis of materials. It is an instrument that records the intensity and diffracted angle of x-ray radiation. Each crystalline solid has its unique characteristic X-ray powder pattern which may be used as a "fingerprint" for its identification. Once the material has been identified, X-ray crystallography may be used to determine its structure, i.e. how the atoms pack together in the crystalline state and what the interatomic distance and angle are etc.

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